Comprehensive performance and robustness analysis of 2D turn models for network-on-chips
Azad, Siavoosh Payandeh; **Niazmand, Behrad**; **Janson, Karl**; Kogge, Thilo; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas**
2017 IEEE International Symposium on Circuits and Systems (ISCAS) 2017 / p. 1476-1479 : ill
https://doi.org/10.1109/ISCAS.2017.8050634 Conference proceedings at Scopus Article at Scopus Article at WOS